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**AUSTRALIAN ATOMIC ENERGY COMMISSION
RESEARCH ESTABLISHMENT
LUCAS HEIGHTS**

PROMPT NUCLEAR ANALYSIS BIBLIOGRAPHY 1976

by

**J.R. BIRD
B.L. CAMPBELL
R.J. CAWLEY**

May 1978

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ABSTRACT

A prompt nuclear analysis bibliography published in 1974 has been updated to include literature up to the end of 1976. The number of publications has more than doubled since mid-1973. The bibliography is now operated as a computer file and searches can be made on key words and parameters. Tables of references are given for each of the categories: backscattering, ion-ion, ion-gamma, ion-neutron, neutron-gamma, neutron-neutron and gamma-ray-induced reactions.

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The following descriptors have been selected from the INIS Thesaurus to describe the subject content of this report for information retrieval purposes. For further details please refer to IAEA-INIS-12 (INIS: Manual for Indexing) and IAEA-INIS-13 (INIS: Thesaurus) published in Vienna by the International Atomic Energy Agency.

BIBLIOGRAPHIES; MICROANALYSIS; NUCLEAR REACTION ANALYSIS;
PROMPT GAMMA RADIATION; PROMPT NEUTRONS; QUANTITATIVE CHEMICAL
ANALYSIS; CHARGED PARTICLES

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1. DESCRIPTION

Prompt nuclear analysis has been defined [Bird, Campbell & Price 1974] as the use of prompt radiation accompanying a nuclear reaction to determine elemental or isotopic concentrations. The use of the range of techniques covered by this definition continues to expand rapidly, the literature having more than doubled in three years. The bibliography published in 1974 (covering literature up to mid-1973) has therefore been updated to include literature to the end of 1976. To facilitate additions to the bibliography and searches for references relating to particular nuclides or specific techniques, a computer record has been developed, together with appropriate search techniques [Cawley & Bird 1978].

1.1 Scope

Nuclear reactions induced by positive ions, neutrons or gamma rays provide the main basis for prompt nuclear analysis. However, ion back-scattering has become a well established tool for analytical work and, rather than attempt to distinguish non-nuclear from nuclear scattering, it is convenient to include high energy scattering techniques within the scope of prompt nuclear analysis.

A number of analytical techniques have been developed using low energy ions for which nuclear interactions are extremely rare. An arbitrary cutoff point has been adopted at an incident ion energy of 100 keV, below which most applications are not included. This cutoff point does not apply to neutron irradiations, thermal neutron interactions being an important field of application.

Product radiation resulting from scattering or nuclear reactions includes positive ions, neutrons or gamma rays. Other product radiations such as X-rays, light, *etc.* which may also accompany irradiations are not included in this bibliography.

In general, the study of the processes involved in nuclear reactions, scattering and channelling, has not been included unless it has involved the use of these processes to determine sample composition. Likewise, the bibliography is not concerned with the physics, chemistry, metallurgy, *etc.* of materials, but only with the development of the methods of prompt nuclear analysis. Papers which contain results based on the use of prompt nuclear analysis, but which contain no information on the techniques used, are included in the record; these are specially marked so that they may be excluded during searches.

There are a number of well established techniques which do not involve the prompt detection of radiation by instrumental methods and these have also been omitted. They include neutron radiography, particle track detection techniques, and all forms of activation analysis as well as logging techniques which depend on properties of a medium such as density or neutron moderating power.

1.2 Computer File

The computer file can contain the following information fields for each publication:

- Code; File number;
- Author(s); Reference;
- Abstract number(s); Title or abstract;
- Reactions: including all sample nuclides and all reactions for which information is given in the publication;
- Description: defining the type of analysis reported, such as film thickness, depth profile, *etc.*;
- Sample material, size, thickness;
- Beam information;
- Radiation detected: type, energy, angle;
- Method, including detector, parameters measured, duration, *etc.*;
- Results, such as yield, accuracy, corrections, sensitivity, *etc.*;
- Reference data reported;
- Field of application.

The information on sample, beam measurements and results is only summarised for publications which have been available as full text and which report significant work or useful summaries. The bibliography is thus designed to serve two functions - as a guide to the literature on prompt nuclear analysis for specific nuclides or specific reactions, and as a compilation of important parameters useful in prompt nuclear analysis work. However, only the first seven information fields are included in this report.

1.3 Searches

Searches of the computer file may be carried out for any combination of characters occurring in specific information fields. Those records which satisfy the search criteria may be listed in whole or in

part, thus providing either a summary or an index to the relevant literature.

Tables 1-9 illustrate the use of such searches to provide indexes of publications reporting prompt nuclear analysis work using specific types of incident and product radiation. In Table 1, only the code number is listed for those publications involving charged particle backscattering or channelling studies. The remaining tables list both code and the reactions used for publications involving each of the major types of nuclear reaction.

The search facility is quite general and, for example, can be used to locate publications by a particular author or from a particular conference, or it can satisfy several criteria such as the study of a particular reaction at a particular energy.

2. BIBLIOGRAPHY

References are listed in alphabetical order of the code which comprises the first three letters of the first author's name and the last two digits of the year of publication (Table 9). Some references appeared first as a report or conference paper and later as a journal paper; these are given the year of the first publication. Multiple references with the same code are listed in arbitrary order with the addition of A, B, C, etc. after the year. An asterisk after the code indicates that this reference was listed in the earlier bibliography.

In addition to the usual element symbols (in capital letters), the following symbols are used to define the reactions reported:

- A - alpha particle (^4He)
- BS - backscattering
- CP - charged particle
- CH - channelling
- D - deuteron (^2H)
- FI - fission
- FS - forward scattering
- G - gamma ray (may be associated with any other reaction product)
- N - neutron
- T - triton

Other symbols used are:

REV - a review paper

THY - theory

& - reactions applying to the same target nuclide(s).

It has not been possible to check some entries in the bibliography which were derived from cross references in other publications. They have been retained when the available information indicated that they are relevant to the subject of prompt nuclear analysis.

3. ACKNOWLEDGEMENT

We wish to thank J. Trimble, D. Williams and A. Bird for assistance in the preparation of the computer file.

4. REFERENCES

Bird, J.R. Campbell, B.L. & Price, P.B. [1974] - Prompt Nuclear Analysis.

At. Energy Rev., 12 (2) 275-342.

Cawley, R.J. & Bird, J.R. [1978] - BIBLIO - A Bibliographic Index System.

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TABLE 1INDEX OF BACKSCATTERING PUBLICATIONS

*PROTON BACKSCATTERING

AKS 75	AND 66 *	ANT 72 *	ARM 71B	ARM 72 *	BAU 71	BAU 73B
BEH 69	BFH 71	BEH 73A	BEH 73B	BJU 70	BLE 73	BLE 74A
BLE 74B	BLE 75	BLE 76	BOG 65	BOG 67A *	BOG 67B	BOG 69B
BOR 70	BUT 73B	BRO 68	BUC 70	BUC 72A	BUE 62 *	CAM 75
CHA 71	CHU 68	COH 71 *	COH 73	CGO 70 *	COO 72A *	COO 73
COO 75	COU 76	DAV 68A	DAV 71C	DEA 64	DEA 73B	DEA 76B
DEL 71	DEL 72 *	DEM 72B *	DEM 72C *	ECK 73	EDG 67 *	EIS 70
EIS 71B	ERI 66	ERI 67	FID 72	FOS 72	FOT 71	GEM 71
GEM 72	GRE 62 *	HAB 72E	HAB 73 *	HAR 70	HAR 71A	HAR 71B
HAR 71D	HEI 72 *	HEM 71 *	JOH 69 *	JON 72 *	KAT 69 *	KRA 75
LAN 76C	LAN 76D	LEG 76	LEM 72A	LEM 72B	MCK 76	MOL 71
MUL 76	MUS 76A	MUS 76B	MYE 74A	MYE 74B	NAM 75	NEL 74A
NEL 74B	NCL 75	PEI 65A *	PEI 65B *	PEI 73A	PIC 69B	PIC 71B
PIC 72A	PIC 73B	PIC 73C	PIC 73E	POA 70B *	POW 62	POW 68
PRO 74C	ROT 74A	ROT 74B	ROT 74C	RUB 50 *	RUB 57 *	RUB 59 *
SCO 76	SIP 59 *	SIR 72	THO 75B	TOE 76	VAN 70	VAN 73A
VAN 73B	VAS 66	VIA 73	VOO 71	WEI 71	WEI 73	WEN 52 *
WES 69	WES 70 *	WHI 67	WHI 69B	WIL 71	WIN 76	ZHU 72
ZLO 72						

*DEUTERON BACKSCATTERING

ABE 69 *	AND 66 *	BAE 75A	BUE 62 *	CAM 72	DEL 71	DEL 75B
KAW 67	MAT 71 *	ROT 76A	SIP 59 *	TUR 68C *	TUR 69A *	TUR 72A *
TUR 72B *						

*3HE BACKSCATTERING

EDG 67 *	LAN 73B	LAN 74	LAN 76C	PIC 75B	TUR 68C *	TUR 69A *
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*ALPHA PARTICLE BACKSCATTERING

ABE 72B *	ABE 72C	ABE 75	AGI 75A	AKA 73B	AKU 74	ALE 70A
ALE 70B	ALE 72 *	ALE 73A *	ALE 73B	ALI 71 *	AND 66 *	AND 71A
ANO 61 *	ANT 72 *	APP 70	ARM 71A	ARM 72 *	BAE 76	BAG 74A
BAG 74B	BAR 69B	BAR 75	BAR 76B	BAU 73A	BAU 73B	BAY 73
BEH 73B	BLO 74	BOG 67A *	BOG 68 *	BOG 69A *	BOG 69B	BOG 70
BUG 72	BOR 71	BOR 72	BOR 73	BOR 74A	BOR 74B	BOT 73A
BUT 73C	BOW 72	BOW 73A	BOW 73B	BOW 73C	BRA 76	BRO 72
BRO 73B	BUC 70	BUC 72A	BUC 72B	BUC 73 *	BUR 68 *	CAM 73
CAM 74A	CAM 74B	CAM 75	CAN 74	CAN 75	CAR 70	CAY 72
CAY 73	CHE 73 *	CHI 71 *	CHU 70	CHU 69	CHU 73B	CHU 73C
CHU 73E	CHU 73F	CHU 74A	CHU 74B	CHU 74C	CHU 75B	CHU 75C
CLA 76	CRO 71B *	CRO 72B	CSE 75	CSE 76	DAV 67B *	DAV 68A
DAV 68B	DAV 71B *	DEA 74	DEA 75C	DEB 74	DEB 75	DEL 70A
DEL 71	DEL 75A	DEW 74	DIE 74	DUN 74	ECO 70 *	ECO 73A *
ECO 73B	ECO 76	EIS 70	EIS 71A	EIS 73A	EIS 73B	ERI 68
ERI 69A	ERI 69C	ERI 72 *	ESK 62 *	FEL 70A	FEL 70B	FEL 71
FEL 72	FEL 73B	FEN 73A	FEN 73B	FIN 75	FON 73	FRA 63 *
FRA 70A	FRA 70B	FUJ 72A	FUJ 72B	FUR 73A	FUR 73B	FUR 73C *
GAN 76	GAV 76	GET 09	GEM 71	GET 74	GOT 75A	GOT 75B
GOT 76	GRO 73A	GRO 73B	GYU 70A *	GYU 70B	GYU 71A *	GYU 71B *
GYU 71C	HAB 70 *	HAB 72A *	HAG 73	HAR 70	HAR 71B	HAR 71C
HAR 72A *	HAR 72B	HAR 73A	HAR 73B	HAR 73C	HAR 74	HAS 71
HAS 72	HIR 71A	HIR 71B	HIR 71C	HIR 71D	HIR 72A	HIR 72B
HIR 72C	HUT 72	ITO 71	IUE 71	IWA 71 *	JOH 70A *	JOL 71A *
JOL 71B *	KAL 76	KAM 71	KAM 72A	KAM 72B	KAU 73	KIR 73
KNU 70 *	KNU 72 *	KRA 71	KRA 74A	KRA 74B	KRA 75	LAN 71
LAN 73A	LAN 76D	LAR 69 *	LAU 74	LAU 76	LEE 71A	LEE 72 *
LEE 73	LIN 73A	LIN 73B	LIN 73C	LIN 73D	LUO 64 *	LUT 68 *
MAC 73A	MAC 73B	MAC 74A	MAC 74C	MAN 72B	MAR 69B	MAR 70
MAR 72	MAS 71	MAT 69	MAT 71 *	MAY 67	MAY 68 *	MAY 71
MAY 72A	MAY 73A	MAY 73B	MAY 74B	MCK 76	MEE 73	MEE 74A
MEE 74B	MEE 75A	MEE 75B	MER 71A	MEY 71B	MER 73	MES 73
MEY 70A *	MEY 70B	MEY 70C	MEY 70D	MEY 71 *	MEY 72	MEY 73

MEY 74	MIL 73	MIT 71A *	MIT 71B	MIT 71C *	MUG 76	MOR 72A *
MOR 72B *	MOR 73B	MUL 71	MUL 73	MYE 73	MYE 74B	MYE 74C
NAK 75	NAK 76	NAM 75	NOR 70B	OLI 75D	OTT 72	OTT 74
PAT 65 *	PAT 66 *	PAT 69 *	PAT 70	PEI 65A *	PEI 66B *	PEI 67B *
PEI 69A *	PEI 69B *	PEI 72B	PEI 73A	PEI 73B	PEI 76	PET 72
PET 73A	PET 73B	PIC 69B	PIC 69C	PIC 69D	PIC 71A	PIC 72B
PIC 73A	PIC 73D	PIC 73E	PIC 74A	PIC 74C	PIE 69 *	PIE 71B
PIE 72A *	PIE 72D *	PIE 74A	POA 69 *	POA 70A *	POA 73A *	POA 73B
POA 73C	POA 73D	POA 74	POA 75	PON 71	PRO 71	PRO 74C
RIC 74	RIG 76	RIM 72A	RIM 72B	SAB 75	SCH 73	SCH 74A
SEI 73	SEI 75A	SEM 64 *	SIG 71B	SIG 73	SIG 74A	SIG 74B
SIL 74	SIN 73	SUF 73	SWA 74	THO 69 *	THU 71	THO 74B
THO 75B	TIN 71	TOE 76	TOU 75	TSU 70	TU 73	TU 75
TUR 61 *	TUR 65 *	TUR 66 *	TUR 67A	TUR 67B *	TUR 68A	TUR 68B
TUR 68C *	TUR 69A *	TUR 69B	TUR 71A *	TUR 73A *	TUR 73D	TUR 74A
VAN 70	VAN 74	VAN 75	VAN 76	VAR 76A	WAR 72	WES 69
WES 70 *	WES 73	WHI 67	WHI 69A	WHI 71C	WIL 66 *	WIL 74
WIL 75B	WIS 74	WOO 75	YAM 76	ZIE 71 *	ZIE 72A *	ZIE 72B *
ZIE 72E	ZIE 73B	ZIE 73C	ZIE 73D	ZIE 73E	ZIE 73F	ZIE 74A
ZIE 74B	ZIF 75B					

*6LI BACKSCATTERING

TAR 74

*11B BACKSCATTERING

VAN 70

*12C BACKSCATTERING

ABE 72B *	ABE 73	ALE 74	AMS 72B *	BER 68	BJO 68 *	BJO 70
CHU 74C	DAV 68A	DOM 70 *	ERI 69B	FEL 72	FLA 69	GUT 71
GUT 73	GUT 74	HAR 73A	HVA 71	JOH 70A *	KAR 66 *	KAU 73

*13C BACKSCATTERING

MUL 76

*14N BACKSCATTERING

ABE 73	ALE 73A *	ALE 73B	ALE 74	ANT 72 *	BOG 69A *	CHU 74C
DIE 74	FEL 72	KAU 73	PEI 69B *	PEI 73A	POA 70A *	

*160 BACKSCATTERING

DAV 68A	MUL 76	PET 73A	PET 73B	PIC 73A	SCH 74B	SEA 71 *
SWI 75B	WAR 72					

*20NE BACKSCATTERING

BER 68

*35CL BACKSCATTERING

DAV 68A LEC 76A WAR 72

*40AR BACKSCATTERING

BER 68

*84KR BACKSCATTERING

BER 68

*CHARGED PARTICLE BACKSCATTERING

ABE 72A	AGI 75B	AMS 72A *	AMS 72C *	AMS 72F	AND 72B *	ASH 76
BAR 76C	BIR 72	BIR 74	BIR 75A	BOG 67A *	BOG 68 *	BOG 73
BOR 74A	BRI 68	BRI 73A	BRU 75	BUC 75	BUR 61 *	CAH 71 *
CAM 76	CHU 73A	CHU 73D	CHU 75A	CHU 75C	CONF 70	CZA 75
DAT 75	DAV 67A	DAV 73B	DEA 73A	DEA 73C	DEA 75A	DEA 75B
EDG 67 *	EIS 73C	ERI 72 *	ESK 62 *	GRA 73	GRU 73B	GYU 72 *
JAC 73	JOL 71A *	KAT 71 *	KEL 76	KHA 74	KRI 72 *	LAN 75
LAN 76B	LOR 75A	MAC 69C *	MAC 72B *	MAC 74B	MAR 76A	MAY 73C

MAY 74A	MAY 75	MEY 76	MEZ 74	MOR 73A	MUE 74	NIC 72 *
PAL 70	PAR 70 *	PEI 66B *	PEI 69B *	PIC 75A	PIE 71A *	PIE 72B *
RUB 54	RUB 55 *	RUB 57 *	RUB 63 *	RUB 70 *	RUG 71	SIP 63 *
SIR 71 *	SNY 50 *	THO 73A	TOW 76	TUR 68C *	TUR 69A *	TUR 72B *
VIE 73	VOO 68	WHE 75	WHI 73B	WOL 72 *	WOL 74	ZIE 73A *
ZIE 75A	ZIE 76A	ZIE 76B				

*FORWARD SCATTERING

BAE 75B	COH 72A *	JAR 74	LEG 76	MEE 72 *	PIE 72E	PIE 74E
SMI 74	WOL 72 *					

*CHANNELLING

ABE 69 *	ABE 73	ABE 75	AKA 73A	AKA 73B	AKU 74	ALE 70A
ALE 70B	ALE 72 *	ALE 73A*	ALE 73B	ALE 74	AND 65 *	AND 67A
AND 70	AND 71A	AND 71B	AND 72A *	APP 70	ARM 71B	ARM 72 *
ASH 76	BAE 75A	BAE 76	BAR 69B	BAR 71A	BAU 71	BAU 73A
BEH 71	BER 68	BIE 73	BIE 75B	BIE 75C	BJO 68 *	BJO 70
BOG 65	BOG 67A*	BOG 67B	BOG 68 *	BOG 69A*	BOG 69B	BOG 70
BUG 72	BOG 73	BON 75	BOR 70	BOT 73A	BOT 73B	BOT 73C
BRI 68	BRO 68	BUC 72A	BUC 72B	BUG 76	CAM 71	CAM 72
CAM 75	CAN 75	CAR 70	CAR 72	CHA 71	CHU 73E	CLA 76
CONF 70	CSE 75	CSE 76	DAT 67	DAT 75	DAV 67A	DAV 67B*
DAV 68A	DAV 68B	DAV 70A	DAV 70B	DAV 71B *	DAV 71C	DAV 73B
DEA 73A	DEA 75A	DEL 70A	DEL 71	DEL 75A	DEL 75B	DEW 74
DOM 70 *	EDG 70	EIS 68	EIS 70	EIS 71A	EIS 71B	EIS 72
EIS 73A	EIS 73B	EIS 73C	ERI 66	ERI 67	ERI 68	ERI 69C
FEL 66	FEL 70A	FEL 70B	FEL 71	FEL 72	FEL 73A	FID 72
FLA 69	FLA 70	FOT 71	FUJ 72A	FUJ 72B	FUJ 75	GEM 71
GEM 72	GET 74	GIB 68	GRA 73	GRO 73A	GYU 70A *	GYU 71A *
GYU 71B *	GYU 71C	GYU 71D	GYU 72 *	HAR 70	HAR 71A	HAR 71B *
HAR 71D	HAR 72B	HAS 71	HAS 72	HIR 70	HIR 71C	HIR 71D
HUT 72	HVA 71	TUE 71	JOH 70A *	KAU 73	KEI 60	KOM 70
KRA 71	KRA 74B	KUM 72A	KUM 72B	LAN 71	LAR 69 *	LEE 71A
LEE 72 *	LIN 65	LIN 73D	LUG 73	MAC 69C *	MAC 73A	MAC 74B
MAR 69B	MAR 72	MAS 71	MAT 69	MAT 71 *	MAY 67	MAY 68 *
MAY 70	MAY 71	MAY 72A	MAY 72B	MAY 73C	MER 71B	MER 73
MEY 70A *	MEY 70B	MEY 70C	MEY 70D	MEY 71*	MIL 73	MIT 71A *
MIT 71B	MIT 71C *	MOR 68	MOR 70A	MOR 70B	MOR 72A *	MOR 73A
MOR 73B	NAK 75	NAM 75	NIC 72 *	NOR 70A	NOR 70B	OHT 72
PAL 70	PAR 70 *	PAT 72	PEL 75	PET 72	PIC 69A	PIC 69B
PIC 69C	PIC 69D	PIC 71B	PIC 72A	PIC 72B	PIC 73B	PIC 73C
PIC 73D	PIC 73E	PIC 74A	PIC 75A	PIC 75B	POA 69 *	POA 70A *
POA 70B *	POA 73A*	POA 73C	POA 73D	PON 71	PRO 71	PRO 74C
RIC 74	RIM 72A	RIM 72B	ROT 74B	RUG 71	RYA 72	SAT 67
SEL 76	SHI 72	SIG 71A	SIG 73	SIG 74B	STA 12	SWA 74
THO 73A	TOW 76	TSU 70	VAN 71A	VAN 71B	VAN 73A	VAN 73B
VLA 72	VOO 68	VOO 71	WEI 71	WES 69	WES 70 *	WHI 69B
WHI 71C	WHI 73B	WIL 71	WIN 72	WOL 72 *	WOO 75	ZHU 72
ZIE 72A *	ZIE 72E					

*PROTON TRANSMISSION

AND 68 *	DEA 73B	DEA 75C	KEN 72 *	MAC 76	SHI 72	VAS 66
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*ALPHA PARTICLE TRANSMISSION

BAD 56	EIS 72	GAV 76	JOL 71B *	MAC 76	MEZ 76	NOR 76
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TABLE 2

INDEX OF ION-ION PUBLICATIONS

* (P,D) REACTIONS

JAR 75
 2D(P,D);3T(P,T)
 JUH 69 *
 12C,14N,16O(P,BS) & (P,G) & (P,D)

* (P,T) REACTIONS

JAR 75
 2D(P,D);3T(P,T)

* (P,A) REACTIONS

ABE 72A
 REV(CP,BS) & (P,A) & (D,P)
 ABE 72C
 O,N,F,AL,SI,S,AR,CA,NB(HE,BS);12C,16O(D,P);14N(D,A);18O(P,A);19F,
 27AL(P,G)
 AGI 73
 16O(D,P);18O(P,A)
 AGI 75A
 FE,AS(HE,BS);16O(D,P);18O(P,A)
 AKA 73A
 11B(P,A) & (CH)
 AKA 73B
 11B(P,A);B,SI(HE,BS) & (CH)
 ALL 76
 18O(P,A);12C,16O(D,P);14N(D,A)
 AMS 62 *
 18O(P,A) ; 27AL(P,G)
 AMS 63 *
 16O(D,P) ; 18O(P,A)
 AMS 67 *
 18O(P,A) ; 12C,16O,18O(D,P) ; 16O,18O(D,A)
 AMS 68A *
 15N,18O(P,A) ; 12C,14N,16O,18O(D,P) ; 14N,18O,29SI,30SI(D,A)
 AMS 69B *
 2D,14N,16O,32S(D,P);14N(D,A);18O(P,A)
 AMS 71A
 2D,12C,16O(D,P);14N(D,A);18O,19F(P,A);19F(P,G)
 AMS 71B *
 REV(D,P) & (D,A) & (P,A) ; 2D,12C,16O(D,P) ; 14N(D,A) ; 18O,19F(P,
 A) ; 19F,27AL(P,G)
 AMS 72B *
 FE,SB(12C,BS);16O(D,P);18O(P,A)
 AMS 72D
 16O(D,P);18O(P,A)
 AMS 72E
 16O(D,P);18O(P,A)
 AMS 75
 18O(P,A)
 AND 72A *
 11B(P,A) & (CH)
 ASH 76
 REV(CP,BS);REV(CH);REV(D,P) & (P,A)
 BAR 69A*
 19F(P,A)
 BAR 73A
 18O(P,A)
 BAR 74
 18O(P,A)
 BER 72 *
 REV(P,A) & (D,P) & (D,A) ; 2D,12C,14N,16O(D,P) ; 14N,29SI,30SI(D,A)
 BOI 74
 16O(D,P);18O(P,A)

BUN 75
 11B,19F(P,A) & (CH)
 BRA 76
 12C,160(D,P);180,19F(P,A);160,MG(HE,BS)
 BRU 72B
 11B,180,31P(P,A)
 BRU 73
 11B,180,31P(P,A)
 BRU 74
 160(P,G);180(P,A)
 BUR 61 *
 (CP,BS);(P,A);(D,P)
 CAL 72 *
 180(P,A)
 CAL 74
 180(P,A)
 CAM 75
 C,N,SI(HE,BS) & (P,BS) & (CH);15N(P,A)
 CHE 73 *
 160(D,P);180(P,A);AL,S(HE,BS)
 CHU 65 *
 180(P,A)
 COE 75C
 6LI,7LI(P,A);6LI(D,A)
 CHO 71A *
 160(D,P);180(P,A)
 CRO 73D
 160(D,P);19F(P,A)
 DAV 71A *
 180(P,A)
 DEA 75C
 O,CR,FE,NI,SN,PB(HE,BS);160(P,P);7LI(P,A)
 DER 70 *
 180(P,A)
 DER 71 *
 180(P,A)
 EDG 70
 6LI,19F(P,A) & (CH)
 ERI 66
 27AL(P,G) & (CH);7LI,11B(P,A) & (CH);SI,W(P,BS) & (CH)
 FEU 69
 2H(D,P);160(D,P);180(P,A)
 FLA 70
 11B(P,A) & (CH)
 FUJ 75
 27AL(P,A) & (CH)
 GAR 72 *
 19F(P,A)
 GAS 73 *
 180(P,A)
 GOL 74A
 7LI,19F(P,A);12C,14N(D,P);14N(D,A);LI,BE,B,C,N,O,F(P,G)
 GRO 75
 180(P,A)
 HER 72A *
 180(P,A)
 HER 72B *
 180(P,A)
 JOL 71B *
 C,N,O,NA,AL,P,CL,CA(HE,BS);12C,160,170,27AL,56FE,58NI(HE,HE);(P,A)
 KEN 72 *
 12C,160(P,P) & (P,A)
 LEE 71B *
 180(P,A)
 LEE 76
 180(P,A)
 LIG 70A *
 180(P,A)
 LIG 71 *
 6LI,11B,15N,180,19F(P,A);160(D,P)
 LIG 72A
 31P(P,A)
 LIG 72B
 11B(P,A)

LIG 73
 11B, 180 (P,A)
 LIG 74C
 11B, 15N (P,A)
 LIG 76
 11B (P,A)
 MAK 66 *
 180 (P,A)
 MAK 67 *
 180 (P,A) ; 15N (P,G)
 MAR 69A*
 180 (P,A)
 MAU 72 *
 160 (D,P) ; 19F (P,A) ; 19F (P,G)
 MCM 76B
 11B (P,A) ; 10B, 12C, 14N (D,P) ; 14N (D,A) ; 10B, 11B (A,P)
 MOO 75
 11B (P,A) ; 160 (D,P)
 MUL 71
 B, SI (HE, BS) ; 19F (P,A)
 NEI 72 *
 180 (P,A)
 NOR 70A
 11B (P,A) & (CH)
 NOR 70B
 11B (P,A) & (HE, BS) & (CH)
 NOR 74
 11B, 180 (P,A)
 OBE 73
 19F (P,A)
 OBE 74
 19F (P,A)
 OLI 74B
 11B (P,A)
 PAL 65 *
 180 (P,A)
 PEL 75
 11B (P,A) & (CH)
 PRE 72C *
 6LI, 7LI (P,A) ; 6LI (D,A)
 PRI 68 *
 180 (P,A)
 PRI 69A*
 180 (P,A)
 ROB 71 *
 180 (P,A)
 SAB 67 *
 180 (P,A) ; 12C, 15N (P,G)
 SIE 71 *
 160 (D,P) ; 180 (P,A)
 SIE 72A
 160 (D,P) ; 180 (P,A)
 SIE 72B
 160 (D,P) ; 180 (P,A)
 SKA 71 *
 180 (P,A)
 WHI 71B *
 180 (P,A)
 WIS 74
 SI, RH (HE, BS) ; 180 (P,A)

* (D,P) REACTIONS

ABE 69 *
 O, SI (D, BS) & (CH) ; 160 (D,P)
 ABE 72A
 REV (CP, BS) & (P,A) & (D,P)
 ABE 72C
 O, N, F, AL, SI, S, AR, CA, NB (HE, BS) ; 12C, 160 (D,P) ; 14N (D,A) ; 180 (P,A) ; 19F,
 27AL (P,G)
 ABE 75
 160 (D,P) ; FE (HE, BS) & (CH)
 AGI 73
 160 (D,P) ; 180 (P,A)
 AGI 75A

FE, AS (HE, BS); 160 (D, P); 180 (P, A)
 ALL 76
 180 (P, A); 12C, 160 (D, P); 14N (D, A)
 AMS 63 *
 160 (D, P); 180 (P, A)
 AMS 67 *
 180 (P, A); 12C, 160, 180 (D, P); 160, 180 (D, A)
 AMS 68A *
 15N, 180 (P, A); 12C, 14N, 160, 180 (D, P); 14N, 180, 29SI, 30SI (D, A)
 AMS 68B *
 160 (D, P)
 AMS 68C *
 160 (D, P)
 AMS 69A *
 160 (D, P)
 AMS 69B *
 2D, 14N, 160, 32S (D, P); 14N (D, A); 180 (P, A)
 AMS 69C *
 14N (D, P) & (D, A)
 AMS 69E *
 12C, 160 (D, P); 29SI, 30SI (D, A)
 AMS 71A
 2D, 12C, 160 (D, P); 14N (D, A); 180, 19F (P, A); 19F (P, G)
 AMS 71B *
 REV (D, P) & (D, A) & (P, A); 2D, 12C, 160 (D, P); 14N (D, A); 180, 19F (P, A); 19F, 27AL (P, G)
 AMS 72B *
 FE, SB (12C, BS); 160 (D, P); 180 (P, A)
 AMS 72D
 160 (D, P); 180 (P, A)
 AMS 72E
 160 (D, P); 180 (P, A)
 AMT 75
 12C, 14N, 160, 32S (D, P) & (D, A)
 AND 66 *
 12C, 13C, 160, CL, MG, SI, TI, CR, MN, FE, AG, PT, PB (P, BS) & (D, BS) & (HE, BS);
 12C, 160, 24MG, 25MG, 27AL, 28SI (D, P)
 ASH 76
 REV (CP, BS); REV (CH); REV (D, P) & (P, A)
 BAI 76
 12C, 160 (D, P); 14N (D, A); 12C, 15N, 160 (P, G)
 BAR 68 *
 12C, 160 (D, P)
 BAR 70 *
 12C, 160 (D, P)
 BEH 75A
 3HE (D, P)
 BEH 75B
 3HE (D, P)
 BER 70 *
 160 (D, P)
 BER 72 *
 REV (P, A) & (D, P) & (D, A); 2D, 12C, 14N, 160 (D, P); 14N, 29SI, 30SI (D, A)
 BER 75A
 12C, 160 (D, P); 14N, 19F (D, A)
 BOI 72B *
 160 (D, P)
 BOI 74
 160 (D, P); 180 (P, A)
 BOT 75
 1H (19F, G) & (11B, G) & (7LI, G); 2D, 3HE (D, P); 2D (3HE, P); 3HE (D, A); 3H (P, N);
 4HE (10B, N)
 BOT 76B
 1H (19F, G) & (11B, A) & (7LI, G) & (15N, G); 2D (3HE, P) & (D, P); 3T (P, N);
 3HE (D, P); 4HE (10B, N)
 BOT 76C
 1H (19F, G); 3HE (D, P)
 BOU 75
 160 (D, P)
 BRA 76
 12C, 160 (D, P); 180, 19F (P, A); 160, MG (HE, BS)
 BUR 61 *
 (CP, BS); (P, A); (D, P)
 CAC 71A *
 160, 28SI (D, P)

CAC 71B *
160,28SI(D,P)
CAR 72
2D(D,P) & (CH)
CHA 75
12C,14N,160(D,P)
CHE 71C
14N(D,A);160(D,P)
CHE 73 *
160(D,P) ; 180(P,A) ; AL,S(HE,BS)
COE 75B
10B(D,P);11B(D,A)
COO 73
(P,BS) ; 160(D,P)
COO 75
REV(P,BS) & (CP,CP) & (CP,G); 14N(D,P)
COX 69 *
160(D,P)
CRO 70A
14N(D,P)
CRO 71A *
160(D,P) ; 180(P,A)
CRO 71B *
SI,AR(HE,BS) ; 160(D,P) ; 14N(D,A)
CRO 72B
SI,TA(HE,BS) ;160(D,P);14N(D,A)
CRO 72C
14N(D,A);160(D,P)
CRO 73D
160(D,P);19F(P,A)
CUY 68 *
160(D,P)
DEA 76B
160(D,P);160,TI,ZR,CE,TL,BI(P,BS)
DEG 69 *
160(D,P)
DEL 75B
160(D,P) & (CH);TI(D,BS) & (CH)
DIA 71 *
160,27AL(D,P)
ENG 75B
12C(D,P)
ENG 76
12C(D,P);14N(D,A);12C,15N(P,G)
FEL 73A
12C,13C,160(D,P) & (CH)
FEU 69
2H(D,P);160(D,P);180(P,A)
GOL 74A
7LI,19F(P,A);12C,14N(D,P);14N(D,A);LI,BE,B,C,N,O,F(P,G)
GRE 62 *
AS,SN,PB,BI(P,BS) ; 12C,160,32S(D,P)
HOR 74
12C(D,P)
HUF 75
3HE(D,P)
HUF 76
2D(D,P)
JON 72 *
12C,13C,14N,15N,160,180(P,BS) ; 12C,13C(A,N) ; 14N,15N(D,N) ; 160,
180(P,N) ; 14N(D,P)
LEG 76
REV(P,BS) & (P,FS) & (D,P)
LEP 75
160(D,P)
LIG 71 *
6LI,11B,15N,180,19F(P,A) ; 160(D,P)
MAT 71 *
O,U(HE,BS) & (D,BS) & (CH) ; 160(D,P) & (CH)
MAU 72 *
160(D,P) ; 19F(P,A) ; 19F(P,G)
MCM 76B
11B(P,A);10B,12C,14N(D,P);14N(D,A);10B,11B(A,P)
MIT 76
27AL(D,P)

MOL 76
 2D(D,P)
 MOO 75
 11B(P,A) ; 160(D,P)
 OLI 69 *
 CR,NI,CU(D,P)
 OLI 70A *
 NI(D,P)
 OLI 70B *
 CR,NI,CU(D,P)
 OLI 72 *
 10B,14N,25MG,28SI,S,CA,TI,V,CR,SR,TA(D,P)
 OLI 75A
 10B,14N,28SI,32S(D,P);14N(D,A)
 OLI 75B
 14N(D,P) & (D,A)
 OLI 76B
 14N(D,G)&(D,P)
 PAD 74
 1H(7LI,G); 12C(D,P); 19F(P,G)
 PAR 70 *
 REV(D,P) ; REV(P,G) ; REV(CP,BS) & (CH)
 PEI 66A *
 2D,12C,14N,160(D,P)
 PEI 67A *
 2D,12C,14N,160(D,P)
 PEI 68A *
 2C,12C,14N,160(D,P) ; 13C,15N,180,43CA,48CA(P,N)
 PIC 74B
 3HE(D,P) ; 2H(3HE,P)
 PIE 71A *
 REV(CP,BS) ; REV(P,G) ; REV(N,G) ; REV(D,P) ; REV(D,N) ; 2D(G,N)
 PIE 73
 12C(D,P)
 PIE 74A
 REV(CP,G) & (D,P) & (D,A) & (HE,BS)
 PIE 74B
 12C(D,P)
 PIE 76A
 160(D,P)
 PIE 76B
 10B,11B,12C,14N,160(D,P)
 PRO 74A
 3HE(D,P)
 PRO 74B
 2D(3HE,P);3HE(D,P)
 PRO 76
 3HE(D,P);2H(3HE,P)
 QUA 69 *
 12C,160(D,P)
 QUA 70 *
 160(D,P)
 QUA 71B *
 160(D,P) ; 160(D,A) ; 160(T,P)
 QUA 73
 12C,14N,160(D,P);14N(D,A)
 RIG 76
 C,N,O(HE,BS);2D,14N,160,30SI(D,P);14N(D,G)
 ROT 76B
 3HE(D,P)
 RUB 57 *
 THY(CP,BS) ; C,O,SI,P,S,CA,FE,CU,AG,BA,PB(P,BS) ; 19F(P,G) ; 12C,
 160(D,P)
 SCH 76B
 12C,160(D,P)
 SIE 71 *
 160(D,P) ; 180(P,A)
 SIE 72A
 160(D,P);180(P,A)
 SIE 72B
 160(D,P);180(P,A)
 SIP 62 *
 160(D,P) ; 19F(P,G)
 SIP 63 *
 REV(CP,BS) ; REV(D,P) ; REV(P,G)

SUN 74A
 12C, 13C, 14N, 16O (D, P) & (D, A)
 SUN 74B
 14N (D, P)
 SUN 75
 14N (D, P)
 SUN 76A
 14N (D, P)
 SUN 76B
 14N (D, P)
 TAR 74
 O, N, AL, AR (6LI, BS); 14N (D, A); 16O (D, P)
 THO 74A
 10B, 12C, 14N, 16O (D, P); 14N, Q6O, 27AL (D, A)
 THO 75B
 2D, 10B, 11B, 12C, 16O (D, P); 11B, 16O (D, A); 11B, 12C, 16O (P, BS); 10B, 10B (A, P);
 11B, 12C, 14N, 16O (HE, BS); 10B (A, D)
 TUR 72B *
 THY (CP, BS) ; AL, SI, CA, TA, AU (D, BS) ; 12C, 16O (D, P) ; 16O (D, A)
 TUR 73B *
 12C, 16O (D, P) ; 16O (D, A)
 TUR 73C
 16O (D, A) ; 12C, 16O, 28SI (D, P)
 TUR 73E
 12C, 16O (D, P)
 VIA 73
 12C, 16O (P, BS); 10B, 12C, 16O (D, P); 16O (D, A)
 WEB 71 *
 16O (D, P)
 WEB 72 *
 2D, 12C, 14N, 16O (D, P)
 WOL 67 *
 32S (D, P)
 YAT 73
 14N (D, P) & (D, A)

 * (D, 3HE) REACTIONS
 JOH 74
 2D (D, 3HE)

 * (D, A) REACTIONS
 ABE 72C
 O, N, F, AL, SI, S, AR, CA, NB (HE, BS); 12C, 16O (D, P); 14N (D, A); 18O (P, A); 19F,
 27AL (P, G)
 ALL 76
 18O (P, A); 12C, 16O (D, P); 14N (D, A)
 AMS 67 *
 18O (P, A) ; 12C, 16O, 18O (D, P) ; 16O, 18O (D, A)
 AMS 68A *
 15N, 18O (P, A) ; 12C, 14N, 16O, 18O (D, P) ; 14N, 18O, 29SI, 30SI (D, A)
 AMS 69B *
 2D, 14N, 16O, 32S (D, P); 14N (D, A); 18O (P, A)
 AMS 69C *
 14N (D, P) & (D, A)
 AMS 69D *
 14N (D, A)
 AMS 69E *
 12C, 16O (D, P) ; 29SI, 30SI (D, A)
 AMS 71A
 2D, 12C, 16O (D, P); 14N (D, A); 18O, 19F (P, A); 19F (P, G)
 AMS 71B *
 REV (D, P) & (D, A) & (P, A) ; 2D, 12C, 16O (D, P) ; 14N (D, A) ; 18O, 19F (P,
 A) ; 19F, 27AL (P, G)
 AMT 75
 12C, 14N, 16O, 32S (D, P) & (D, A)
 BAI 76
 12C, 16O (D, P); 14N (D, A); 12C, 15N, 16O (P, G)
 BAR 76A
 14N (D, A)
 BAR 76B
 16O (D, A); O, NI, CR, AU (HE, BS)
 BER 72 *
 REV (P, A) & (D, P) & (D, A) ; 2D, 12C, 14N, 16O (D, P) ; 14N, 29SI, 30SI (D, A)

BER 75A
 12C, 160 (D,P) ; 14N, 19F (D,A)
 BOT 75
 1H(19F,G) & (11B,G) & (7LI,G); 2D, 3HE(D,P); 2D(3HE,P); 3HE(D,A); 3H(P,N);
 4HE(10B,N)
 CHE 71C
 14N(D,A); 160(D,P)
 COE 75A
 9BE(D,A)
 COE 75B
 10B(D,P); 11B(D,A)
 COE 75C
 6LI, 7LI(P,A); 6LI(D,A)
 CRO 71B *
 SI, AR(HE, BS) ; 160(D,P) ; 14N(D,A)
 CRO 72B
 SI, TA(HE, BS) ; 160(D,P); 14N(D,A)
 CRO 72C
 14N(D,A); 160(D,P)
 ECK 76
 3HE(D,A)
 ENG 76
 12C(D,P); 14N(D,A); 12C, 15N(P,G)
 FAU 71 *
 160(D,A)
 GOL 74A
 7LI, 19F(P,A); 12C, 14N(D,P); 14N(D,A); LI, BE, B, C, N, O, F(P,G)
 MCM 76B
 11B(P,A); 10B, 12C, 14N(D,P); 14N(D,A); 10B, 11B(A,P)
 OLI 75A
 10B, 14N, 28SI, 32S(D,P); 14N(D,A)
 OLI 75B
 14N(D,P) & (D,A)
 PIE 74A
 REV(CP,G) & (D,P) & (D,A) & (HE,BS)
 PRE 72A *
 6LI(D,A)
 PRE 72B *
 6LI, 7LI(D,A)
 PRE 72C *
 6LI, 7LI(P,A); 6LI(D,A)
 QUA 71B *
 160(D,P) ; 160(D,A) ; 160(T,P)
 QUA 73
 12C, 14N, 160(D,P); 14N(D,A)
 ROT 76A
 3HE(D,A) & (D,BS)
 SUN 74A
 12C, 13C, 14N, 160(D,P) & (D,A)
 TAR 74
 D, N, AL, AR(6LI, BS); 14N(D,A); 160(D,P)
 THO 74A
 10B, 12C, 14N, 160(D,P); 14N, Q60, 27AL(D,A)
 THO 75B
 2D, 10B, 11B, 12C, 160(D,P); 11B, 160(D,A); 11B, 12C, 160(P,BS); 10B, 10B(A,P);
 11B, 12C, 14N, 160(HE,BS); 10B(A,D)
 TUR 72B *
 THY(CP,BS) ; AL, SI, CA, TA, AU(D,BS) ; 12C, 160(D,P) ; 160(D,A)
 TUR 73B *
 12C, 160(D,P) ; 160(D,A)
 TUR 73C
 160(D,A); 12C, 160, 28SI(D,P)
 VIA 73
 12C, 160(P,BS); 10B, 12C, 160(D,P); 160(D,A)
 YAT 73
 14N(D,P) & (D,A)

* (T,P) REACTIONS

BAR 73B
 12C, 160(T,P)
 QUA 71B *
 160(D,P) ; 160(D,A) ; 160(T,P)

* (3HE,P) REACTIONS

BOT 75
 1H(19F,G) & (11B,G) & (7LI,G); 2D, 3HE(D,P); 2D(3HE,P); 3HE(D,A); 3H(P,N);
 4HE(10B,N)
 BOT 76B
 1H(19F,G) & (11B,A) & (7LI,G) & (15N,G); 2D(3HE,P) & (D,P); 3T(P,N);
 3HE(D,P); 4HE(10B,N)
 BUG 76
 1H(11B,A); 2H(3HE,P); (CH)
 MAR 76B
 1H(11B,A); 1H(7LI,G); 2H(3HE,P); 1H(19F,G); 1H(15N,G)
 PIC 74B
 3HE(D,P); 2H(3HE,P)
 PIC 75B
 CR,W(3HE,BS); 2D(3HE,P) & (CH)
 PIC 76A
 1H(19F,G); 2D(3HE,P)
 PRO 74B
 2D(3HE,P); 3HE(D,P)
 PRO 76
 3HE(D,P); 2H(3HE,P)
 SAN 72 *
 C,O(3HE,P)

 * (3HE,A) REACTIONS
 COX 66 *
 17O(3HE,A)
 LAN 73B
 CR,MO,ER(3HE,BS); 2D(3HE,A)
 LAN 74
 CR,MO,ER(3HE,BS); 2D(3HE,A)
 LAN 76C
 2D(3HE,A); 2D,ER,MO(3HE,BS); 2D,3H,3HE,4HE(P,BS)
 OLL 66 *
 17O(3HE,A)
 SCH 76A
 D(3HE,A)

 * (4HE,P) REACTIONS
 ECO 73B
 C,O,F,NA,MG,AL,SI,CA,TI,FE,BA(HE,BS); N(A,P)
 ECO 76
 (HE,BS); N,F,NA,MG,AL,SI(A,P)
 MCM 76B
 11B(P,A); 10B,12C,14N(D,P); 14N(D,A); 10B,11B(A,P)
 OLI 76A
 10B,11B(A,P)
 PAT 65 *
 THY(HE,BS); BE,C,N,O,F,NA,MG,AL,SI,P,S,CL,CA,K,TI,CR,FE,CU,ZR,AG,
 PT(HE,BS); NA,MG,AL,SI(A,P)
 PAT 66 *
 C,N,O,NA,MG,AL,SI,P,S,CL,K,CA,TI,FE,NI(HE,BS); NA,MG,AL,SI(A,P)
 PAT 69 *
 C,N,O,NA,MG,AL,SI,P,S,CL,K,CA,TI,FE,NI(HE,BS); NA,MG,AL,SI(A,P)
 PEI 72B
 O,SI,CA,PB(HE,BS); B,NA,AL(A,P)
 PEI 73B
 O,NA,SI,CA,K,BA(HE,BS); 10B,23NA,27AL(A,P)
 PIE 74D
 10B,11B(A,P)
 THO 75B
 2D,10B,11B,12C,16O(D,P); 11B,16O(D,A); 11B,12C,16O(P,BS); 10B,10B(A,P);
 11B,12C,14N,16O(HE,BS); 10B(A,C)
 TUR 65 *
 (HE,BS); (A,P)
 TUR 66 *
 C,MG,FE(HE,BS); AL,SI,P(A,P)
 TUR 67A
 C,O,MG,SI,CA,FE(HE,BS); NA,MG,AL,SI(A,P)
 TUR 67B *
 C,O,F,NA,MG,AL,SI,P,S,CL,CA,FE,BA(HE,BS); NA,MG,AL,SI(A,P)
 TUR 68A
 C,O,MG,SI,CA,FE(HE,BS); NA,MG,AL,SI(A,P)
 TUR 68B

C,O,MG,SI,CA,FE(HE,BS); NA,MG,AL,SI(A,P)
 TUR 69B
 C,O,MG,SI,CA,FE(HE,BS); NA,MG,AL,SI(A,P)
 TUR 71A *
 C,O,F,NA,MG,AL,SI,S,K,CA,TI,FE,SR,BA(HE,BS) ; NA,MG,AL,SI(A,P)
 TUR 73A *
 C,O,F,NA,MG,AL,SI,S,K,CA,TI,FE,SR,BA(HE,BS) ; NA,MG,AL,SI(A,P)

* (4HE,D) REACTIONS

THO 75B
 2D,10B,11B,12C,16O(D,P);11B,16O(D,A);11B,12C,16O(P,BS); 10B,10B(A,P)
 11B,12C,14N,16O(HE,BS);10B(A,D)

* (6LI,D) REACTIONS

CAR 75
 12C,14N,16O(6LI,D)
 LEC 76B
 7LI,12C,16O(6LI,P);9BE,12C(6LI,D);9BE,10B,11B,16O(6LI,A)

* (11B,A) REACTIONS

BOT 76B
 1H(19F,G) & (11B,A) & (7LI,G) & (15N,G);2D(3HE,P) & (D,P);3T(P,N);
 3HE(D,P);4HE(10B,N)
 BUG 76
 1H(11B,A);2H(3HE,P);(CH)
 GUI 74
 1H(11B,A)
 LIG 74A
 1H(11B,A)
 LIG 74B
 1H(11B,A)
 MAR 76B
 1H(11B,A);1H(7LI,G);2H(3HE,P);1H(19F,G);1H(15N,G)

* (CP,CP) REACTIONS

AGI 75B
 (CP,BS) ;(CP,CP)
 AMS 72A*
 REV(CP,BS) & (CP,CP)
 AMS 72C *
 REV(CP,BS) & (CP,CP)
 AMS 72F
 REV(CP,BS);REV(CP,CP)
 AMS 73
 REV(CP,CP)
 BAU 76
 (CP,CP)
 BIR 72
 REV(CP,BS) & (CP,CP) & (CP,G) & (CP,N) & (N,CP) & (N,G) & (G,G) &
 (G,N)
 BIR 74
 REV(CP,BS) & (CP,CP) & (CP,G) & (CP,N) & (N,CP) & (N,G) & (G,G) & (G,
 N)
 BIR 75A
 REV(CP,BS) & (CP,CP) & (CP,G) & (N,G);F,NA,AL(P,G)
 BIR 76
 REV(CP,CP)&(CP,G)&(CP,N)&(N,CP)&(N,G)&(G,G)
 BLA 73
 (CP,CP)
 BRU 75
 REV(CP,BS) & (CP,CP) & (CP,G)
 CAM 76
 REV(CP,BS) & (CP,G) & (CP,CP) & (N,G)
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* (4HE,G) REACTIONS

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 4HE(10B,N)
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 3HE(D,P);4HE(10B,N)
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 1H(7LI,G)
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 3HE(D,P); 4HF(10B,N)
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* (19F,G) REACTIONS

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 BOT 76B
 1H(19F,G) & (11B,A) & (7LI,G) & (15N,G); 2D(3HE,P) & (D,P); 3T(P,N);
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 (G,N)
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 N)
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 MAC 68B *
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* (4HE,N) REACTIONS

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 1H(19F,G) & (11B,G) & (7LI,G);2D,3HE(D,P);2D(3HE,P);3HE(D,A);3H(P,N);
 4HE(10B,N)
 BOT 76B
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 3HE(D,P);4HE(10B,N)

* (CP,N) REACTIONS

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 (G,N)
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 REV(CP,BS) & (CP,CP) & (CP,G) & (CP,N) & (N,CP) & (N,G) & (G,G) & (G,
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 BIR 76
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